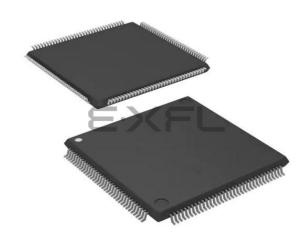
E ·) (Fartice Semiconductor Corporation - <u>LCMX02-1200HC-6TG144C Datasheet</u>



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	160
Number of Logic Elements/Cells	1280
Total RAM Bits	65536
Number of I/O	107
Number of Gates	-
Voltage - Supply	2.375V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmxo2-1200hc-6tg144c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Figure 2-4. Slice Diagram



For Slices 0 and 1, memory control signals are generated from Slice 2 as follows:

- WCK is CLK
 WRE is from LSR
- DI[3:2] for Slice 1 and DI[1:0] for Slice 0 data from Slice 2
- WAD [A:D] is a 4-bit address from slice 2 LUT input

 Table 2-2. Slice Signal Descriptions

Function	Туре	Signal Names	Description
Input	Data signal	A0, B0, C0, D0	Inputs to LUT4
Input	Data signal	A1, B1, C1, D1	Inputs to LUT4
Input	Multi-purpose	M0/M1	Multi-purpose input
Input	Control signal	CE	Clock enable
Input	Control signal	LSR	Local set/reset
Input	Control signal	CLK	System clock
Input	Inter-PFU signal	FCIN	Fast carry in ¹
Output	Data signals	F0, F1	LUT4 output register bypass signals
Output	Data signals	Q0, Q1	Register outputs
Output	Data signals	OFX0	Output of a LUT5 MUX
Output	Data signals	OFX1	Output of a LUT6, LUT7, LUT8 ² MUX depending on the slice
Output	Inter-PFU signal	FCO	Fast carry out ¹

1. See Figure 2-3 for connection details.

2. Requires two PFUs.



ROM Mode

ROM mode uses the LUT logic; hence, slices 0-3 can be used in ROM mode. Preloading is accomplished through the programming interface during PFU configuration.

For more information on the RAM and ROM modes, please refer to TN1201, Memory Usage Guide for MachXO2 Devices.

Routing

There are many resources provided in the MachXO2 devices to route signals individually or as buses with related control signals. The routing resources consist of switching circuitry, buffers and metal interconnect (routing) segments.

The inter-PFU connections are made with three different types of routing resources: x1 (spans two PFUs), x2 (spans three PFUs) and x6 (spans seven PFUs). The x1, x2, and x6 connections provide fast and efficient connections in the horizontal and vertical directions.

The design tools take the output of the synthesis tool and places and routes the design. Generally, the place and route tool is completely automatic, although an interactive routing editor is available to optimize the design.

Clock/Control Distribution Network

Each MachXO2 device has eight clock inputs (PCLK [T, C] [Banknum]_[2..0]) – three pins on the left side, two pins each on the bottom and top sides and one pin on the right side. These clock inputs drive the clock nets. These eight inputs can be differential or single-ended and may be used as general purpose I/O if they are not used to drive the clock nets. When using a single ended clock input, only the PCLKT input can drive the clock tree directly.

The MachXO2 architecture has three types of clocking resources: edge clocks, primary clocks and secondary high fanout nets. MachXO2-640U, MachXO2-1200/U and higher density devices have two edge clocks each on the top and bottom edges. Lower density devices have no edge clocks. Edge clocks are used to clock I/O registers and have low injection time and skew. Edge clock inputs are from PLL outputs, primary clock pads, edge clock bridge outputs and CIB sources.

The eight primary clock lines in the primary clock network drive throughout the entire device and can provide clocks for all resources within the device including PFUs, EBRs and PICs. In addition to the primary clock signals, MachXO2 devices also have eight secondary high fanout signals which can be used for global control signals, such as clock enables, synchronous or asynchronous clears, presets, output enables, etc. Internal logic can drive the global clock network for internally-generated global clocks and control signals.

The maximum frequency for the primary clock network is shown in the MachXO2 External Switching Characteristics table.

The primary clock signals for the MachXO2-256 and MachXO2-640 are generated from eight 17:1 muxes The available clock sources include eight I/O sources and 9 routing inputs. Primary clock signals for the MachXO2-640U, MachXO2-1200/U and larger devices are generated from eight 27:1 muxes The available clock sources include eight I/O sources, 11 routing inputs, eight clock divider inputs and up to eight sysCLOCK PLL outputs.



Table 2-4. PLL Signal Descriptions (Continued)

Port Name	I/O	Description
CLKOP	0	Primary PLL output clock (with phase shift adjustment)
CLKOS	0	Secondary PLL output clock (with phase shift adjust)
CLKOS2	0	Secondary PLL output clock2 (with phase shift adjust)
CLKOS3	0	Secondary PLL output clock3 (with phase shift adjust)
LOCK	0	PLL LOCK, asynchronous signal. Active high indicates PLL is locked to input and feed- back signals.
DPHSRC	0	Dynamic Phase source – ports or WISHBONE is active
STDBY	I	Standby signal to power down the PLL
RST	I	PLL reset without resetting the M-divider. Active high reset.
RESETM	I	PLL reset - includes resetting the M-divider. Active high reset.
RESETC	I	Reset for CLKOS2 output divider only. Active high reset.
RESETD	I	Reset for CLKOS3 output divider only. Active high reset.
ENCLKOP	I	Enable PLL output CLKOP
ENCLKOS	I	Enable PLL output CLKOS when port is active
ENCLKOS2	I	Enable PLL output CLKOS2 when port is active
ENCLKOS3	I	Enable PLL output CLKOS3 when port is active
PLLCLK	I	PLL data bus clock input signal
PLLRST	I	PLL data bus reset. This resets only the data bus not any register values.
PLLSTB	I	PLL data bus strobe signal
PLLWE	I	PLL data bus write enable signal
PLLADDR [4:0]	I	PLL data bus address
PLLDATI [7:0]	ļ	PLL data bus data input
PLLDATO [7:0]	0	PLL data bus data output
PLLACK	0	PLL data bus acknowledge signal

sysMEM Embedded Block RAM Memory

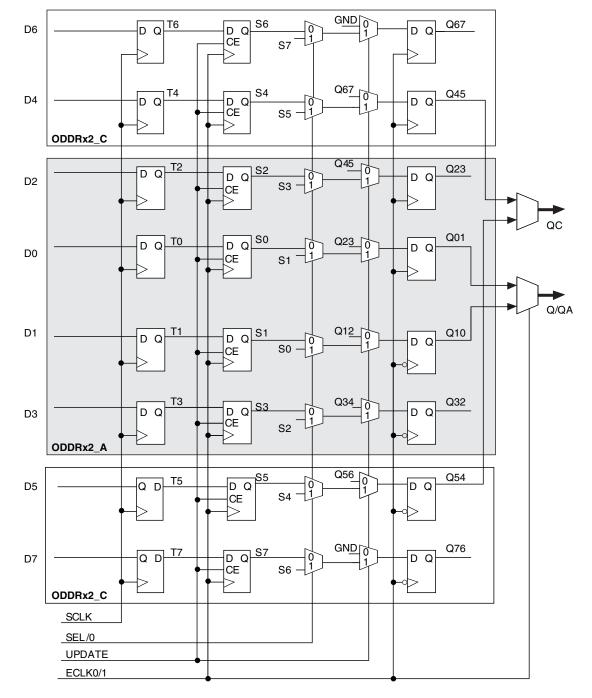
The MachXO2-640/U and larger devices contain sysMEM Embedded Block RAMs (EBRs). The EBR consists of a 9-kbit RAM, with dedicated input and output registers. This memory can be used for a wide variety of purposes including data buffering, PROM for the soft processor and FIFO.

sysMEM Memory Block

The sysMEM block can implement single port, dual port, pseudo dual port, or FIFO memories. Each block can be used in a variety of depths and widths as shown in Table 2-5.



Figure 2-17. Output Gearbox



More information on the output gearbox is available in TN1203, Implementing High-Speed Interfaces with MachXO2 Devices.



DDR Memory Support

Certain PICs on the right edge of MachXO2-640U, MachXO2-1200/U and larger devices, have additional circuitry to allow the implementation of DDR memory interfaces. There are two groups of 14 or 12 PIOs each on the right edge with additional circuitry to implement DDR memory interfaces. This capability allows the implementation of up to 16-bit wide memory interfaces. One PIO from each group contains a control element, the DQS Read/Write Block, to facilitate the generation of clock and control signals (DQSR90, DQSW90, DDRCLKPOL and DATAVALID). These clock and control signals are distributed to the other PIO in the group through dedicated low skew routing.

DQS Read Write Block

Source synchronous interfaces generally require the input clock to be adjusted in order to correctly capture data at the input register. For most interfaces a PLL is used for this adjustment. However, in DDR memories the clock (referred to as DQS) is not free-running so this approach cannot be used. The DQS Read Write block provides the required clock alignment for DDR memory interfaces. DQSR90 and DQSW90 signals are generated by the DQS Read Write block from the DQS input.

In a typical DDR memory interface design, the phase relationship between the incoming delayed DQS strobe and the internal system clock (during the read cycle) is unknown. The MachXO2 family contains dedicated circuits to transfer data between these domains. To prevent set-up and hold violations, at the domain transfer between DQS (delayed) and the system clock, a clock polarity selector is used. This circuit changes the edge on which the data is registered in the synchronizing registers in the input register block. This requires evaluation at the start of each read cycle for the correct clock polarity. Prior to the read operation in DDR memories, DQS is in tri-state (pulled by termination). The DDR memory device drives DQS low at the start of the preamble state. A dedicated circuit in the DQS Read Write block detects the first DQS rising edge after the preamble state and generates the DDRCLKPOL signal. This signal is used to control the polarity of the clock to the synchronizing registers.

The temperature, voltage and process variations of the DQS delay block are compensated by a set of calibration signals (6-bit bus) from a DLL on the right edge of the device. The DLL loop is compensated for temperature, voltage and process variations by the system clock and feedback loop.

sysIO Buffer

Each I/O is associated with a flexible buffer referred to as a sysIO buffer. These buffers are arranged around the periphery of the device in groups referred to as banks. The sysIO buffers allow users to implement a wide variety of standards that are found in today's systems including LVCMOS, TTL, PCI, SSTL, HSTL, LVDS, BLVDS, MLVDS and LVPECL.

Each bank is capable of supporting multiple I/O standards. In the MachXO2 devices, single-ended output buffers, ratioed input buffers (LVTTL, LVCMOS and PCI), differential (LVDS) and referenced input buffers (SSTL and HSTL) are powered using I/O supply voltage (V_{CCIO}). Each sysIO bank has its own V_{CCIO} . In addition, each bank has a voltage reference, V_{REF} which allows the use of referenced input buffers independent of the bank V_{CCIO} .

MachXO2-256 and MachXO2-640 devices contain single-ended ratioed input buffers and single-ended output buffers with complementary outputs on all the I/O banks. Note that the single-ended input buffers on these devices do not contain PCI clamps. In addition to the single-ended I/O buffers these two devices also have differential and referenced input buffers on all I/Os. The I/Os are arranged in pairs, the two pads in the pair are described as "T" and "C", where the true pad is associated with the positive side of the differential input buffer and the comp (complementary) pad is associated with the negative side of the differential input buffer.



Hot Socketing

The MachXO2 devices have been carefully designed to ensure predictable behavior during power-up and powerdown. Leakage into I/O pins is controlled to within specified limits. This allows for easy integration with the rest of the system. These capabilities make the MachXO2 ideal for many multiple power supply and hot-swap applications.

On-chip Oscillator

Every MachXO2 device has an internal CMOS oscillator. The oscillator output can be routed as a clock to the clock tree or as a reference clock to the sysCLOCK PLL using general routing resources. The oscillator frequency can be divided by internal logic. There is a dedicated programming bit and a user input to enable/disable the oscillator. The oscillator frequency ranges from 2.08 MHz to 133 MHz. The software default value of the Master Clock (MCLK) is nominally 2.08 MHz. When a different MCLK is selected during the design process, the following sequence takes place:

- 1. Device powers up with a nominal MCLK frequency of 2.08 MHz.
- 2. During configuration, users select a different master clock frequency.
- 3. The MCLK frequency changes to the selected frequency once the clock configuration bits are received.
- 4. If the user does not select a master clock frequency, then the configuration bitstream defaults to the MCLK frequency of 2.08 MHz.

Table 2-14 lists all the available MCLK frequencies.

Table 2-14. Available MCLK Frequencies

MCLK (MHz, Nominal)	MCLK (MHz, Nominal)	MCLK (MHz, Nominal)
2.08 (default)	9.17	33.25
2.46	10.23	38
3.17	13.3	44.33
4.29	14.78	53.2
5.54	20.46	66.5
7	26.6	88.67
8.31	29.56	133

Embedded Hardened IP Functions and User Flash Memory

All MachXO2 devices provide embedded hardened functions such as SPI, I²C and Timer/Counter. MachXO2-640/U and higher density devices also provide User Flash Memory (UFM). These embedded blocks interface through the WISHBONE interface with routing as shown in Figure 2-20.



For more details on these embedded functions, please refer to TN1205, Using User Flash Memory and Hardened Control Functions in MachXO2 Devices.

User Flash Memory (UFM)

MachXO2-640/U and higher density devices provide a User Flash Memory block, which can be used for a variety of applications including storing a portion of the configuration image, initializing EBRs, to store PROM data or, as a general purpose user Flash memory. The UFM block connects to the device core through the embedded function block WISHBONE interface. Users can also access the UFM block through the JTAG, I²C and SPI interfaces of the device. The UFM block offers the following features:

- Non-volatile storage up to 256 kbits
- 100K write cycles
- Write access is performed page-wise; each page has 128 bits (16 bytes)
- Auto-increment addressing
- WISHBONE interface

For more information on the UFM, please refer to TN1205, Using User Flash Memory and Hardened Control Functions in MachXO2 Devices.

Standby Mode and Power Saving Options

MachXO2 devices are available in three options for maximum flexibility: ZE, HC and HE devices. The ZE devices have ultra low static and dynamic power consumption. These devices use a 1.2 V core voltage that further reduces power consumption. The HC and HE devices are designed to provide high performance. The HC devices have a built-in voltage regulator to allow for 2.5 V V_{CC} and 3.3 V V_{CC} while the HE devices operate at 1.2 V V_{CC}.

MachXO2 devices have been designed with features that allow users to meet the static and dynamic power requirements of their applications by controlling various device subsystems such as the bandgap, power-on-reset circuitry, I/O bank controllers, power guard, on-chip oscillator, PLLs, etc. In order to maximize power savings, MachXO2 devices support an ultra low power Stand-by mode. While most of these features are available in all three device types, these features are mainly intended for use with MachXO2 ZE devices to manage power consumption.

In the stand-by mode the MachXO2 devices are powered on and configured. Internal logic, I/Os and memories are switched on and remain operational, as the user logic waits for an external input. The device enters this mode when the standby input of the standby controller is toggled or when an appropriate I²C or JTAG instruction is issued by an external master. Various subsystems in the device such as the band gap, power-on-reset circuitry etc can be configured such that they are automatically turned "off" or go into a low power consumption state to save power when the device enters this state. Note that the MachXO2 devices are powered on when in standby mode and all power supplies should remain in the Recommended Operating Conditions.



Device Subsystem	Feature Description
Bandgap	The bandgap can be turned off in standby mode. When the Bandgap is turned off, ana- log circuitry such as the POR, PLLs, on-chip oscillator, and referenced and differential I/O buffers are also turned off. Bandgap can only be turned off for 1.2 V devices.
Power-On-Reset (POR)	The POR can be turned off in standby mode. This monitors VCC levels. In the event of unsafe V_{CC} drops, this circuit reconfigures the device. When the POR circuitry is turned off, limited power detector circuitry is still active. This option is only recommended for applications in which the power supply rails are reliable.
On-Chip Oscillator	The on-chip oscillator has two power saving features. It may be switched off if it is not needed in your design. It can also be turned off in Standby mode.
PLL	Similar to the on-chip oscillator, the PLL also has two power saving features. It can be statically switched off if it is not needed in a design. It can also be turned off in Standby mode. The PLL will wait until all output clocks from the PLL are driven low before powering off.
I/O Bank Controller	Referenced and differential I/O buffers (used to implement standards such as HSTL, SSTL and LVDS) consume more than ratioed single-ended I/Os such as LVCMOS and LVTTL. The I/O bank controller allows the user to turn these I/Os off dynamically on a per bank selection.
Dynamic Clock Enable for Primary Clock Nets	Each primary clock net can be dynamically disabled to save power.
Power Guard	Power Guard is a feature implemented in input buffers. This feature allows users to switch off the input buffer when it is not needed. This feature can be used in both clock and data paths. Its biggest impact is that in the standby mode it can be used to switch off clock inputs that are distributed using general routing resources.

For more details on the standby mode refer to TN1198, Power Estimation and Management for MachXO2 Devices.

Power On Reset

MachXO2 devices have power-on reset circuitry to monitor V_{CCINT} and V_{CCIO} voltage levels during power-up and operation. At power-up, the POR circuitry monitors V_{CCINT} and V_{CCIO0} (controls configuration) voltage levels. It then triggers download from the on-chip configuration Flash memory after reaching the V_{PORUP} level specified in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. For devices without voltage regulators (ZE and HE devices), V_{CCINT} is the same as the V_{CC} supply voltage. For devices with voltage regulators (HC devices), V_{CCINT} is regulated from the V_{CC} supply voltage. From this voltage reference, the time taken for configuration and entry into user mode is specified as Flash Download Time (t_{REFRESH}) in the DC and Switching Characteristics section of this data sheet. Before and during configuration, the I/Os are held in tristate. I/Os are released to user functionality once the device has finished configuration. Note that for HC devices, a separate POR circuit monitors external V_{CC} voltage in addition to the POR circuit that monitors the internal post-regulated power supply voltage level.

Once the device enters into user mode, the POR circuitry can optionally continue to monitor V_{CCINT} levels. If V_{CCINT} drops below $V_{PORDNBG}$ level (with the bandgap circuitry switched on) or below $V_{PORDNSRAM}$ level (with the bandgap circuitry switched off to conserve power) device functionality cannot be guaranteed. In such a situation the POR issues a reset and begins monitoring the V_{CCINT} and V_{CCIO} voltage levels. $V_{PORDNBG}$ and $V_{PORDNSRAM}$ are both specified in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet.

Note that once a ZE or HE device enters user mode, users can switch off the bandgap to conserve power. When the bandgap circuitry is switched off, the POR circuitry also shuts down. The device is designed such that a minimal, low power POR circuit is still operational (this corresponds to the $V_{PORDNSRAM}$ reset point described in the paragraph above). However this circuit is not as accurate as the one that operates when the bandgap is switched on. The low power POR circuit emulates an SRAM cell and is biased to trip before the vast majority of SRAM cells flip. If users are concerned about the V_{CC} supply dropping below V_{CC} (min) they should not shut down the bandgap or POR circuit.



When implementing background programming of the on-chip Flash, care must be taken for the operation of the PLL. For devices that have two PLLs (XO2-2000U, -4000 and -7000), the system must put the RPLL (Right-side PLL) in reset state during the background Flash programming. More detailed description can be found in TN1204, MachXO2 Programming and Configuration Usage Guide.

Security and One-Time Programmable Mode (OTP)

For applications where security is important, the lack of an external bitstream provides a solution that is inherently more secure than SRAM-based FPGAs. This is further enhanced by device locking. MachXO2 devices contain security bits that, when set, prevent the readback of the SRAM configuration and non-volatile Flash memory spaces. The device can be in one of two modes:

- 1. Unlocked Readback of the SRAM configuration and non-volatile Flash memory spaces is allowed.
- 2. Permanently Locked The device is permanently locked.

Once set, the only way to clear the security bits is to erase the device. To further complement the security of the device, a One Time Programmable (OTP) mode is available. Once the device is set in this mode it is not possible to erase or re-program the Flash and SRAM OTP portions of the device. For more details, refer to TN1204, MachXO2 Programming and Configuration Usage Guide.

Dual Boot

MachXO2 devices can optionally boot from two patterns, a primary bitstream and a golden bitstream. If the primary bitstream is found to be corrupt while being downloaded into the SRAM, the device shall then automatically re-boot from the golden bitstream. Note that the primary bitstream must reside in the on-chip Flash. The golden image MUST reside in an external SPI Flash. For more details, refer to TN1204, MachXO2 Programming and Configuration Usage Guide.

Soft Error Detection

The SED feature is a CRC check of the SRAM cells after the device is configured. This check ensures that the SRAM cells were configured successfully. This feature is enabled by a configuration bit option. The Soft Error Detection can also be initiated in user mode via an input to the fabric. The clock for the Soft Error Detection circuit is generated using a dedicated divider. The undivided clock from the on-chip oscillator is the input to this divider. For low power applications users can switch off the Soft Error Detection circuit. For more details, refer to TN1206, MachXO2 Soft Error Detection Usage Guide.

TraceID

Each MachXO2 device contains a unique (per device), TraceID that can be used for tracking purposes or for IP security applications. The TraceID is 64 bits long. Eight out of 64 bits are user-programmable, the remaining 56 bits are factory-programmed. The TraceID is accessible through the EFB WISHBONE interface and can also be accessed through the SPI, I²C, or JTAG interfaces.

Density Shifting

The MachXO2 family has been designed to enable density migration within the same package. Furthermore, the architecture ensures a high success rate when performing design migration from lower density devices to higher density devices. In many cases, it is also possible to shift a lower utilization design targeted for a high-density device to a lower density device. However, the exact details of the final resource utilization will impact the likely success in each case. When migrating from lower to higher density or higher to lower density, ensure to review all the power supplies and NC pins of the chosen devices. For more details refer to the MachXO2 migration files.



LVDS Emulation

MachXO2 devices can support LVDS outputs via emulation (LVDS25E). The output is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs on all devices. The scheme shown in Figure 3-1 is one possible solution for LVDS standard implementation. Resistor values in Figure 3-1 are industry standard values for 1% resistors.





Note: All resistors are ±1%.

Table 3-1. LVDS25E DC Conditions

Over Recommended Operating Conditions

_									
Parameter	Description	Тур.	Units						
Z _{OUT}	Output impedance	20	Ohms						
R _S	Driver series resistor	158	Ohms						
R _P	Driver parallel resistor	140	Ohms						
R _T	Receiver termination	100	Ohms						
V _{OH}	Output high voltage	1.43	V						
V _{OL}	Output low voltage	1.07	V						
V _{OD}	Output differential voltage	0.35	V						
V _{CM}	Output common mode voltage	1.25	V						
Z _{BACK}	Back impedance	100.5	Ohms						
I _{DC}	DC output current	6.03	mA						



Typical Building Block Function Performance – ZE Devices¹

Pin-to-Pin Performance (LVCMOS25 12 mA Drive)

Function	–3 Timing	Units	
Basic Functions			
16-bit decoder	13.9	ns	
4:1 MUX	10.9	ns	
16:1 MUX	12.0	ns	

Register-to-Register Performance

–3 Timing	Units
191	MHz
134	MHz
148	MHz
77	MHz
90	MHz
214	MHz
	191 134 148 77 90

1. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.

Derating Logic Timing

Logic timing provided in the following sections of the data sheet and the Lattice design tools are worst case numbers in the operating range. Actual delays may be much faster. Lattice design tools can provide logic timing numbers at a particular temperature and voltage.



MachXO2 External Switching Characteristics – HC/HE Devices^{1, 2, 3, 4, 5, 6, 7}

			-	6	_	5	-4		
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
Clocks									
Primary Clo	ocks								
f _{MAX_PRI} ⁸	Frequency for Primary Clock Tree	All MachXO2 devices		388		323		269	MHz
t _{W_PRI}	Clock Pulse Width for Primary Clock	All MachXO2 devices	0.5		0.6		0.7		ns
		MachXO2-256HC-HE	_	912	—	939	—	975	ps
		MachXO2-640HC-HE		844		871		908	ps
	Primary Clock Skew Within a	MachXO2-1200HC-HE		868		902		951	ps
^t SKEW_PRI	Device	MachXO2-2000HC-HE		867		897		941	ps
		MachXO2-4000HC-HE		865	—	892		931	ps
		MachXO2-7000HC-HE	—	902	—	942	—	989	ps
Edge Clock	1	1			I.		1		L
f _{MAX_EDGE} ⁸	Frequency for Edge Clock	MachXO2-1200 and larger devices	_	400	_	333	_	278	MHz
Pin-LUT-Pin	Propagation Delay								
t _{PD}	Best case propagation delay through one LUT-4	All MachXO2 devices	_	6.72	_	6.96	_	7.24	ns
General I/O	Pin Parameters (Using Primar	y Clock without PLL)					1		
		MachXO2-256HC-HE	_	7.13	—	7.30	—	7.57	ns
		MachXO2-640HC-HE		7.15	—	7.30		7.57	ns
	Clock to Output – PIO Output	MachXO2-1200HC-HE	_	7.44	—	7.64	—	7.94	ns
t _{CO}	Register	MachXO2-2000HC-HE	_	7.46	—	7.66	—	7.96	ns
		MachXO2-4000HC-HE		7.51	—	7.71		8.01	ns
		MachXO2-7000HC-HE	_	7.54	—	7.75	—	8.06	ns
		MachXO2-256HC-HE	-0.06	_	-0.06		-0.06		ns
		MachXO2-640HC-HE	-0.06	_	-0.06	_	-0.06	_	ns
	Clock to Data Setup – PIO	MachXO2-1200HC-HE	-0.17	_	-0.17		-0.17		ns
t _{SU}	Input Register	MachXO2-2000HC-HE	-0.20	_	-0.20		-0.20		ns
		MachXO2-4000HC-HE	-0.23	_	-0.23	_	-0.23	_	ns
		MachXO2-7000HC-HE	-0.23	—	-0.23	_	-0.23	—	ns
		MachXO2-256HC-HE	1.75	_	1.95	_	2.16	—	ns
		MachXO2-640HC-HE	1.75	—	1.95	—	2.16	_	ns
	Clock to Data Hold – PIO Input	MachXO2-1200HC-HE	1.88	_	2.12		2.36	_	ns
t _H	Register	MachXO2-2000HC-HE	1.89	_	2.13	_	2.37	_	ns
		MachXO2-4000HC-HE	1.94	—	2.18	_	2.43	_	ns
		MachXO2-7000HC-HE	1.98	_	2.23	—	2.49	—	ns

Over Recommended Operating Conditions



			_	-6	_	-5	-4		
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
LPDDR ^{9, 12}			l		L	I		L	<u> </u>
t _{DVADQ}	Input Data Valid After DQS Input		_	0.369	_	0.395	_	0.421	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.529	_	0.530	_	0.527	_	UI
t _{DQVBS}	Output Data Invalid Before DQS Output	MachXO2-1200/U and	0.25	_	0.25	_	0.25	_	UI
t _{DQVAS}	Output Data Invalid After DQS Output	larger devices, right side only. ¹³	0.25	_	0.25	_	0.25	_	UI
f _{DATA}	MEM LPDDR Serial Data Speed		_	280	_	250	—	208	Mbps
f _{SCLK}	SCLK Frequency			140	—	125		104	MHz
f _{LPDDR}	LPDDR Data Transfer Rate		0	280	0	250	0	208	Mbps
DDR ^{9, 12}			•						
t _{DVADQ}	Input Data Valid After DQS Input		_	0.350	_	0.387	_	0.414	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.545	_	0.538	_	0.532	_	UI
t _{DQVBS}	Output Data Invalid Before DQS Output	MachXO2-1200/U and larger devices, right	0.25	_	0.25	_	0.25	_	UI
t _{DQVAS}	Output Data Invalid After DQS Output	side only. ¹³	0.25	_	0.25	_	0.25	_	UI
f _{DATA}	MEM DDR Serial Data Speed		—	300	—	250	—	208	Mbps
f _{SCLK}	SCLK Frequency		—	150	—	125	—	104	MHz
f _{MEM_DDR}	MEM DDR Data Transfer Rate		N/A	300	N/A	250	N/A	208	Mbps
DDR2 ^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input		_	0.360	_	0.378	_	0.406	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.555	_	0.549	_	0.542	_	UI
t _{DQVBS}	Output Data Invalid Before DQS Output	MachXO2-1200/U and	0.25	_	0.25	_	0.25	_	UI
t _{DQVAS}	Output Data Invalid After DQS Output	larger devices, right side only. ¹³	0.25	_	0.25	_	0.25	_	UI
f _{DATA}	MEM DDR Serial Data Speed			300		250		208	Mbps
f _{SCLK}	SCLK Frequency	1		150	_	125		104	MHz
f _{MEM_DDR2}	MEM DDR2 Data Transfer Rate		N/A	300	N/A	250	N/A	208	Mbps

1. Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.

2. General I/O timing numbers based on LVCMOS 2.5, 8 mA, 0pf load, fast slew rate.

3. Generic DDR timing numbers based on LVDS I/O (for input, output, and clock ports).

4. DDR timing numbers based on SSTL25. DDR2 timing numbers based on SSTL18. LPDDR timing numbers based in LVCMOS18.

5. 7:1 LVDS (GDDR71) uses the LVDS I/O standard (for input, output, and clock ports).

6. For Generic DDRX1 mode $t_{SU} = t_{HO} = (t_{DVE} - t_{DVA} - 0.03 \text{ ns})/2$.

7. The $t_{SU_{DEL}}$ and $t_{H_{DEL}}$ values use the SCLK_ZERHOLD default step size. Each step is 105 ps (-6), 113 ps (-5), 120 ps (-4).

8. This number for general purpose usage. Duty cycle tolerance is +/- 10%.

9. Duty cycle is +/-5% for system usage.

10. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with the device selected.

11. High-speed DDR and LVDS not supported in SG32 (32 QFN) packages.

12. Advance information for MachXO2 devices in 48 QFN packages.

13. DDR memory interface not supported in QN84 (84 QFN) and SG32 (32 QFN) packages.



MachXO2 Oscillator Output Frequency

Symbol	Parameter	Min.	Тур.	Max	Units
f _{MAX}	Oscillator Output Frequency (Commercial Grade Devices, 0 to 85°C)	125.685	133	140.315	MHz
	Oscillator Output Frequency (Industrial Grade Devices, –40 °C to 100 °C)	124.355	133	141.645	MHz
t _{DT}	Output Clock Duty Cycle	43	50	57	%
t _{OPJIT} 1	Output Clock Period Jitter	0.01	0.012	0.02	UIPP
t _{STABLEOSC}	STDBY Low to Oscillator Stable	0.01	0.05	0.1	μs

1. Output Clock Period Jitter specified at 133 MHz. The values for lower frequencies will be smaller UIPP. The typical value for 133 MHz is 95 ps and for 2.08 MHz the typical value is 1.54 ns.

MachXO2 Standby Mode Timing – HC/HE Devices

Symbol	Parameter	Device	Min.	Тур.	Max	Units
t _{PWRDN}	USERSTDBY High to Stop	All	_	—	9	ns
		LCMXO2-256		—		μs
		LCMXO2-640		—		μs
		LCMXO2-640U		—		μs
t _{PWRUP}		LCMXO2-1200	20	—	50	μs
	USERSTDBY Low to Power Up	LCMXO2-1200U		—		μs
		LCMXO2-2000		—		μs
		LCMXO2-2000U		—		μs
		LCMXO2-4000		—		μs
		LCMXO2-7000		—		μs
t _{WSTDBY}	USERSTDBY Pulse Width	All	18	_	_	ns



MachXO2 Standby Mode Timing – ZE Devices

Symbol	Parameter	Device	Min.	Тур.	Max	Units
t _{PWRDN}	USERSTDBY High to Stop	All	_	—	13	ns
		LCMXO2-256		—		μs
		LCMXO2-640		—		μs
	USERSTDBY Low to Power Up	LCMXO2-1200	20	—	50	μs
^t PWRUP		LCMXO2-2000		—		μs
		LCMXO2-4000		—		μs
		LCMXO2-7000		_		μs
t _{WSTDBY}	USERSTDBY Pulse Width	All	19			ns
t _{BNDGAPSTBL}	USERSTDBY High to Bandgap Stable	All		—	15	ns





			MachXO2-1200U			
	100 TQFP	132 csBGA	144 TQFP	25 WLCSP	32 QFN ¹	256 ftBGA
General Purpose I/O per Bank	•					
Bank 0	18	25	27	11	9	50
Bank 1	21	26	26	0	2	52
Bank 2	20	28	28	7	9	52
Bank 3	20	25	26	0	2	16
Bank 4	0	0	0	0	0	16
Bank 5	0	0	0	0	0	20
Total General Purpose Single Ended I/O	79	104	107	18	22	206
Differential I/O per Bank						
Bank 0	9	13	14	5	4	25
Bank 1	10	13	13	0	1	26
Bank 2	10	14	14	2	4	26
Bank 3	10	12	13	0	1	8
Bank 4	0	0	0	0	0	8
Bank 5	0	0	0	0	0	10
Total General Purpose Differential I/O	39	52	54	7	10	103
Dual Function I/O	31	33	33	18	22	33
High-speed Differential I/O						
Bank 0	4	7	7	0	0	14
Gearboxes						
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	4	7	7	0	0	14
Number of 7:1 or 8:1 Input Gearbox Avail- able (Bank 2)	5	7	7	0	2	14
DQS Groups						
Bank 1	1	2	2	0	0	2
VCCIO Pins						
Bank 0	2	3	3	1	2	4
Bank 1	2	3	3	0	1	4
Bank 2	2	3	3	1	2	4
Bank 3	3	3	3	0	1	1
Bank 4	0	0	0	0	0	2
Bank 5	0	0	0	0	0	1
VCC	2	4	4	2	2	8
GND	8	10	12	2	2	24
NC	1	1	8	0	0	1
Reserved for Configuration	1	1	1	1	1	1
Total Count of Bonded Pins	100	132	144	25	32	256
1. Lattice recommends soldering the centra						

1. Lattice recommends soldering the central thermal pad onto the top PCB ground for improved thermal resistance.



MachXO2 Family Data Sheet Ordering Information

March 2017

Data Sheet DS1035

MachXO2 Part Number Description



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High-Performance Commercial Grade Devices with Voltage Regulator, Halogen Free (RoHS) Packaging

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-256HC-4SG32C	256	2.5 V / 3.3 V	-4	Halogen-Free QFN	32	COM
LCMXO2-256HC-5SG32C	256	2.5 V / 3.3 V	-5	Halogen-Free QFN	32	COM
LCMXO2-256HC-6SG32C	256	2.5 V / 3.3 V	-6	Halogen-Free QFN	32	COM
LCMXO2-256HC-4SG48C	256	2.5 V / 3.3 V	-4	Halogen-Free QFN	48	COM
LCMXO2-256HC-5SG48C	256	2.5 V / 3.3 V	-5	Halogen-Free QFN	48	COM
LCMXO2-256HC-6SG48C	256	2.5 V / 3.3 V	-6	Halogen-Free QFN	48	COM
LCMXO2-256HC-4UMG64C	256	2.5 V / 3.3 V	-4	Halogen-Free ucBGA	64	COM
LCMXO2-256HC-5UMG64C	256	2.5 V / 3.3 V	-5	Halogen-Free ucBGA	64	COM
LCMXO2-256HC-6UMG64C	256	2.5 V / 3.3 V	-6	Halogen-Free ucBGA	64	COM
LCMXO2-256HC-4TG100C	256	2.5 V / 3.3 V	-4	Halogen-Free TQFP	100	COM
LCMXO2-256HC-5TG100C	256	2.5 V / 3.3 V	-5	Halogen-Free TQFP	100	COM
LCMXO2-256HC-6TG100C	256	2.5 V / 3.3 V	-6	Halogen-Free TQFP	100	COM
LCMXO2-256HC-4MG132C	256	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	COM
LCMXO2-256HC-5MG132C	256	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	COM
LCMXO2-256HC-6MG132C	256	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-640HC-4SG48C	640	2.5 V / 3.3 V	-4	Halogen-Free QFN	48	COM
LCMXO2-640HC-5SG48C	640	2.5 V / 3.3 V	-5	Halogen-Free QFN	48	COM
LCMXO2-640HC-6SG48C	640	2.5 V / 3.3 V	-6	Halogen-Free QFN	48	COM
LCMXO2-640HC-4TG100C	640	2.5 V / 3.3 V	-4	Halogen-Free TQFP	100	COM
LCMXO2-640HC-5TG100C	640	2.5 V / 3.3 V	-5	Halogen-Free TQFP	100	COM
LCMXO2-640HC-6TG100C	640	2.5 V / 3.3 V	-6	Halogen-Free TQFP	100	COM
LCMXO2-640HC-4MG132C	640	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	COM
LCMXO2-640HC-5MG132C	640	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	COM
LCMXO2-640HC-6MG132C	640	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-640UHC-4TG144C	640	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	COM
LCMXO2-640UHC-5TG144C	640	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	COM
LCMXO2-640UHC-6TG144C	640	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	COM



MachXO2 Family Data Sheet Revision History

March 2017

Data Sheet DS1035

Date	Version	Section	Change Summary
March 2017	3.3	DC and Switching Characteristics	Updated the Absolute Maximum Ratings section. Added standards.
			Updated the sysIO Recommended Operating Conditions section. Added standards.
			Updated the sysIO Single-Ended DC Electrical Characteristics sec- tion. Added standards.
			Updated the MachXO2 External Switching Characteristics – HC/HE Devices section. Under 7:1 LVDS Outputs – GDDR71_TX.ECLK.7:1, the D_{VB} and the D_{VA} parameters were changed to D_{IB} and D_{IA} . The parameter descriptions were also modified.
			Updated the MachXO2 External Switching Characteristics – ZE Devices section. Under 7:1 LVDS Outputs – GDDR71_TX.ECLK.7:1, the D_{VB} and the D_{VA} parameters were changed to D_{IB} and D_{IA} . The parameter descriptions were also modified.
			Updated the sysCONFIG Port Timing Specifications section. Corrected the t_{INITL} units from ns to μ s.
		Pinout Information	Updated the Signal Descriptions section. Revised the descriptions of the PROGRAMN, INITN, and DONE signals.
			Updated the Pinout Information Summary section. Added footnote to MachXO2-1200 32 QFN.
		Ordering Information	Updated the MachXO2 Part Number Description section. Corrected the MG184, BG256, FTG256 package information. Added "(0.8 mm Pitch)" to BG332.
			Updated the Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging section. — Updated LCMXO2-1200ZE-1UWG25ITR50 footnote. — Corrected footnote numbering typo. — Added the LCMXO2-2000ZE-1UWG49ITR50 and LCMXO2- 2000ZE-1UWG49ITR1K part numbers. Updated/added footnote/s.

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Image: space with the second secon	Date	Version	Section	Change Summary
Guide table. Architecture Added information to Standby Mode and Power Saving Options section. Pinout Information Added the XO2-2000 49 WLCSP in the Pinout Information Summary table. Ordering Information Added the XO2-2000 2E in the Pinout Information Summary table. Ordering Information Added the XO2-2000ZE-1UWG49CTR in Ultra Low Power Commercial Grade Devices, Halogen Free (RoHS) Packaging section. Added and LCMXO2-2000ZE-1UWG49ITR in Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging section. Added and LCMXO2-2000ZE-1UWG49ITR in Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging section. December 2013 02.3 Architecture Updated Information on CLKOS output divider in sysCLOCK Phase Locked Loops (PLLs) section. DC and Switching Updated footnote 4 in sysIO Single-Ended DC Electrical Characteristics table; Updated V _{IL} Max. (V) data for LVCMOS 25 and LVCMOS 28. Updated V _{OS} test condition in sysIO Differential Electrical Characteristics - LVDS table. Updated Supported Input Standards table. DC and Switching Updated Power-On-Reset Voltage Levels table. Updated Supported Input Standards table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. June 2013 02.1 Architecture Architec	May 2014	2.5	Architecture	Updated TransFR description for PLL use during background Flash
Image: section of the sectio	February 2014 02.4		Introduction	
Image: series of the series			Architecture	
Added and LCMXO2-2000ZE-1UWG49CTR in Ultra Low Power Commercial Grade Devices, Halogen Free (RoHS) Packaging section. Added and LCMXO2-2000ZE-1UWG49ITR in Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging section. December 2013 02.3 Architecture Updated information on CLKOS output divider in sysCLOCK Phase Locked Loops (PLLs) section. DC and Switching Characteristics Updated Static Supply Current – ZE Devices table. Updated footnote 4 in sysIO Single-Ended DC Electrical Characteris tics table; Updated V _{IL} Max. (V) data for LVCMOS 25 and LVCMOS 28. Updated Vos test condition in sysIO Differential Electrical Characteri- istics - LVDS table. September 2013 02.2 Oz and Switching Characteristics Removed I ² C Clock-Stretching feature per PCN #10A-13. Removed information on PDPR memory in RAM Mode section. Updated Supported Input Standards table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the regis- ter on power up and after configuration. sysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOC KPLL Timing table. Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.			Pinout Information	Added the XO2-2000 49 WLCSP in the Pinout Information Summary table.
Image: bit is a series of the serie			Ordering Information	Added UW49 package in MachXO2 Part Number Description.
Industrial Grade Devices, Halogen Free (RoHS) Packaging section. December 2013 02.3 Architecture Updated information on CLKOS output divider in sysCLOCK Phase Locked Loops (PLLs) section. DC and Switching Characteristics Updated Static Supply Current – ZE Devices table. Updated footnote 4 in sysIO Single-Ended DC Electrical Characteris tics table; Updated V _{IL} Max. (V) data for LVCMOS 25 and LVCMOS 28. September 2013 02.2 Architecture Removed I ² C Clock-Stretching feature per PCN #10A-13. Removed I ² C Clock-Stretching feature per PCN #10A-13. Removed information on PDPR memory in RAM Mode section. Updated Supported Input Standards table. Updated Power-On-Reset Voltage Levels table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. SysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOCK PLL Timing table. DC and Switching Characteristics Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – ED Povices and the MachXO2 External Switching Characteristics – ZE Devices tables.				Commercial Grade Devices, Halogen Free (RoHS) Packaging sec-
DC and Switching Characteristics Updated Static Supply Current – ZE Devices table. Updated footnote 4 in sysIO Single-Ended DC Electrical Characteristics table; Updated footnote 4 in sysIO Single-Ended DC Electrical Characteristics table; Updated V _{IL} Max. (V) data for LVCMOS 25 and LVCMOS 28. September 2013 02.2 Architecture Removed I ² C Clock-Stretching feature per PCN #10A-13. Removed information on PDPR memory in RAM Mode section. Updated Supported Input Standards table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. sysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOCK PLL Timing table. DC and Switching Characteristics DC and Switching Characteristics Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – ZE Devices tables.				
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September 2013 02.2 Architecture Removed I ² C Clock-Stretching feature per PCN #10A-13. Removed information on PDPR memory in RAM Mode section. Updated Supported Input Standards table. DC and Switching Characteristics Updated Power-On-Reset Voltage Levels table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. SysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOCK PLL Timing table. DC and Switching Characteristics DC and Switching Characteristics Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.				Characteristics
June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. SysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOCK PLL Timing table. DC and Switching characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.				Updated $\rm V_{OS}$ test condition in sysIO Differential Electrical Characteristics - LVDS table.
Updated Supported Input Standards table. DC and Switching Characteristics Updated Power-On-Reset Voltage Levels table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. SysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOCK PLL Timing table. DC and Switching Characteristics Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.	September 2013	02.2	Architecture	Removed I ² C Clock-Stretching feature per PCN #10A-13.
DC and Switching Characteristics Updated Power-On-Reset Voltage Levels table. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the regis- ter on power up and after configuration. sysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOCK PLL Timing table. DC and Switching Characteristics Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.				Removed information on PDPR memory in RAM Mode section.
Characteristics Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. June 2013 02.1 Architecture Architecture Overview – Added information on the state of the register on power up and after configuration. sysCLOCK Phase Locked Loops (PLLs) section – Added missing cross reference to sysCLOCK PLL Timing table. DC and Switching Characteristics DC and Switching Characteristics Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.				
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Cross reference to sysCLOCK PLL Timing table. DC and Switching Characteristics Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.	June 2013	02.1	Architecture	
Characteristics Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables.				
Power-On-Reset Voltage Levels table – Added symbols.				Switching Characteristics - HC/HE Devices and the MachXO2 Exter-
				Power-On-Reset Voltage Levels table – Added symbols.



Date	Version	Section	Change Summary			
January 2013	02.0	Introduction	Updated the total number IOs to include JTAGENB.			
		Architecture	Supported Output Standards table – Added 3.3 V_{CCIO} (Typ.) to LVDS row.			
			Changed SRAM CRC Error Detection to Soft Error Detection.			
		DC and Switching Characteristics	Power Supply Ramp Rates table – Updated Units column for t _{RAMP} symbol.			
			Added new Maximum sysIO Buffer Performance table.			
			sysCLOCK PLL Timing table – Updated Min. column values for $f_{\rm IN}, f_{\rm OUT}, f_{\rm OUT2}$ and $f_{\rm PFD}$ parameters. Added $t_{\rm SPO}$ parameter. Updated footnote 6.			
			MachXO2 Oscillator Output Frequency table – Updated symbol name			
			for t _{STABLEOSC} .			
			DC Electrical Characteristics table – Updated conditions for ${\rm I}_{\rm IL,}~{\rm I}_{\rm IH}$ symbols.			
			Corrected parameters tDQVBS and tDQVAS			
			Corrected MachXO2 ZE parameters tDVADQ and tDVEDQ			
		Pinout Information	Included the MachXO2-4000HE 184 csBGA package.			
		Ordering Information	Updated part number.			
April 2012	01.9	Architecture	Removed references to TN1200.			
		Ordering Information	Updated the Device Status portion of the MachXO2 Part Number Description to include the 50 parts per reel for the WLCSP package.			
			Added new part number and footnote 2 for LCMXO2-1200ZE- 1UWG25ITR50.			
			Updated footnote 1 for LCMXO2-1200ZE-1UWG25ITR.			
		Supplemental Information	Removed references to TN1200.			
March 2012	01.8	Introduction	Added 32 QFN packaging information to Features bullets and MachXO2 Family Selection Guide table.			
		DC and Switching Characteristics	Changed 'STANDBY' to 'USERSTDBY' in Standby Mode timing dia- gram.			
		Pinout Information	Removed footnote from Pin Information Summary tables.			
			Added 32 QFN package to Pin Information Summary table.			
		Ordering Information	Updated Part Number Description and Ordering Information tables for 32 QFN package.			
			Updated topside mark diagram in the Ordering Information section.			